

CONTENTS

CONTRIBUTORS TO VOLUME 43	vii
FOREWORD	ix

Electron Micrograph Analysis by Optical Transforms

G. DONELLI AND L. PAOLETTI

I. Introduction	1
II. Image Formation in an Electron Microscope.	2
III. Optical Processing of Electron Microscopic Data	12
IV. Applications	23
References	40

Recent Advances in Electron Beam Addressed Memories

JOHN KELLY

I. Introduction	43
II. Background	44
III. Storage Media	51
IV. Surface Charge Storage	56
V. Bulk Charge Storage	81
VI. Alternative Storage Media	99
VII. Electron-Optical Systems	112
VIII. Beam Memory Systems	129
References	135

Electron Beams as Analytical Tools in Surface Research: LEED and AES

L. FIERMANS AND J. VENNIK

I. Introduction	139
II. Low Energy Electron Diffraction (LEED)	141
III. Auger Electron Spectroscopy (AES)	164
References	198

X-Ray Image Intensifiers

KIRBY G. VOSBURGH, ROBERT K. SWANK, AND JOHN M. HOUSTON

I. Introduction	205
II. Input Phosphors	207
III. Electron Optics	216
IV. Output Phosphors	226
V. XRII Performance	231

VI. Future Trends	238
Selected Bibliography	242
References	243
AUTHOR INDEX	245
SUBJECT INDEX	253